

**ECE1371 Advanced Analog Circuits
Lecture 4**

PIPELINE AND SAR ADCS

Richard Schreier
richard.schreier@analog.com

Trevor Caldwell
trevor.caldwell@utoronto.ca

Course Goals

- **Deepen Understanding of CMOS analog circuit design through a top-down study of a modern analog system**
The lectures will focus on Delta-Sigma ADCs, but you may do your project on another analog system.
- **Develop circuit insight through brief peeks at some nifty little circuits**
The circuit world is filled with many little gems that every competent designer ought to recognize.

Date	Lecture		Ref	Homework
2008-01-07	RS	1	Introduction: MOD1 & MOD2	S&T 2-3, A Matlab MOD2
2008-01-14	RS	2	Example Design: Part 1	S&T 9.1, J&M 10 Switch-level sim
2008-01-21	RS	3	Example Design: Part 2	J&M 14, S&T B Q-level sim
2008-01-28	TC	4	Pipeline and SAR ADCs	J&M 11,13 Pipeline DNL
2008-02-04	ISSCC – No Lecture			
2008-02-11	RS	5	Advanced $\Delta\Sigma$	S&T 4, 6.6, 9.4, B $\Delta\Sigma$ Toolbox; Proj
2008-02-18	Reading Week – No Lecture			
2008-02-25	RS	6	Comparator and Flash ADC	J&M 7
2008-03-03	TC	7	SC Circuits	J&M 10
2008-03-10	TC	8	Amplifier Design	
2008-03-17	TC	9	Amplifier Design	
2008-03-24	TC	10	Noise in SC Circuits	S&T C
2008-03-31	Project Presentations			
2008-04-07	TC	11	Matching & MM-Shaping	Project Report
2008-04-14	RS	12	Switching Regulator	Q-level sim

ECE1371

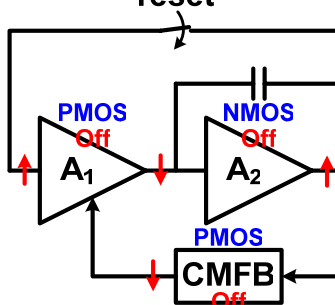
4-3

NLCOTD: Startup Circuit

- Example: Integrator in reset mode

Output tied to input, 2-stage OpAmp

If output CM of A_1 is low, output CM of A_2 is high,
everything turns off



How do we keep this from turning off during reset?

ECE1371

4-4

Highlights

(i.e. What you will learn today)

- 1. Review of ADC performance limitations**
- 2. Basic operation of Pipeline ADCs**
- 3. Basic operation of Successive Approximation ADCs**
- 4. Fundamental trade-offs in ADCs**
Bandwidth, Resolution and Power
Figures of Merit

ECE1371

4-5

Review

- Performance Limitations in ADCs**
 - Offset Error**
 - Gain Error**
 - Integral Nonlinearity (INL) Error**
 - Differential Nonlinearity (DNL) Error**
 - Sampling Time Uncertainty**
 - Missing Codes**
 - Conversion Time and Sampling Rate**

ECE1371

4-6

Offset and Gain Errors

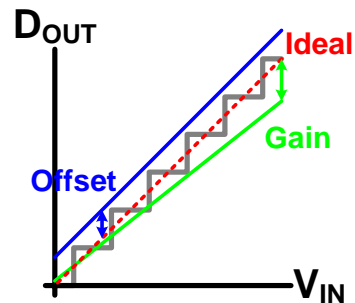
- Look at transition points of input analog voltage
 $V_{0...01}$ is transition from 0 to 1 in output code

- Offset Error

$$E_{off} = \frac{V_{0...01}}{V_{LSB}} - \frac{1}{2} LSB$$

- Gain Error

$$E_{gain} = \left(\frac{V_{1...1}}{V_{LSB}} - \frac{V_{0...01}}{V_{LSB}} \right) - (2^N - 2)$$



ECE1371

4-7

INL and DNL Errors

- Remove Offset and Gain errors before finding INL and DNL error

- INL Error

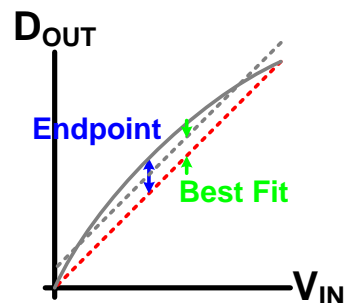
Deviation from straight line

- DNL Error

Transition values should be 1 LSB apart

Error is deviation from 1 LSB

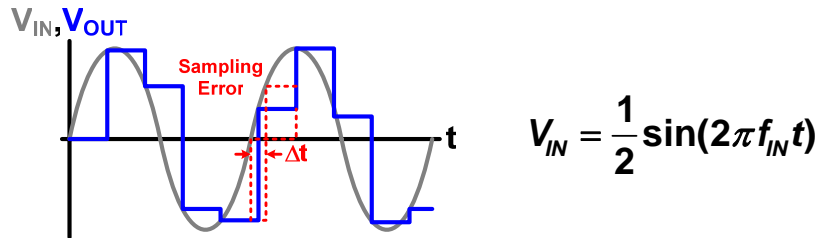
Differentiate INL Error



ECE1371

4-8

Sampling Time Uncertainty



- **Error occurs with uncertainty in sampling time**

Worst case at maximum slope of input signal

$$\left. \frac{\Delta V}{\Delta t} \right|_{\max} = \pi f_{IN}$$

For error less than 1 LSB

$$\Delta t < \frac{1}{2^N \pi f_{IN}}$$

ECE1371

4-9

Other Limitations

- **Missing Codes**

Digital output code never occurs

Guaranteed not to happen if $\max(\text{DNL}) < 1 \text{ LSB}$ or $\max(\text{INL}) < 0.5 \text{ LSB}$

- **Conversion Time and Sampling Rate**

Conversion Time: time for a single measurement, includes latency of converter

Sampling Rate: maximum rate where samples can be continuously converted; not always the inverse of conversion time

ECE1371

4-10

Comparison: Nyquist vs $\Delta\Sigma$ ADCs

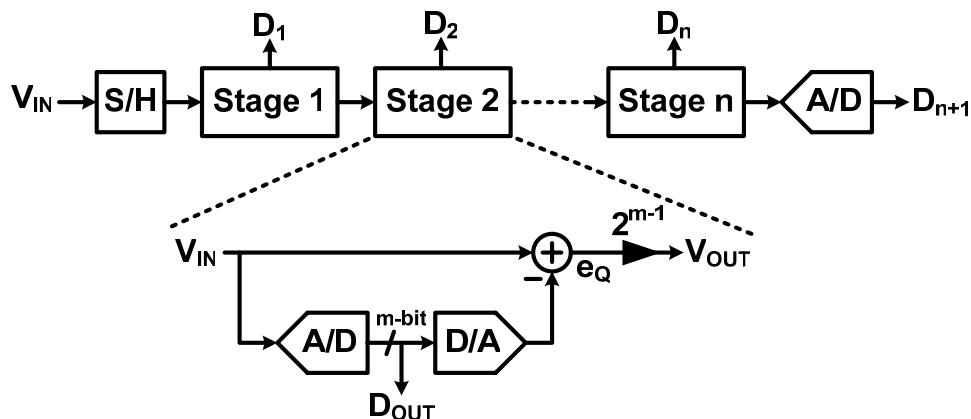
- **Larger bandwidth in Nyquist rate ADCs**
Oversampling costs bandwidth, increases accuracy
- **Nyquist ADC uses entire output spectrum**
- **Noise in $\Delta\Sigma$ primarily important in signal band**
Larger out-of-band shaped noise gets filtered
- **Nyquist ADC digital output has one-to-one correspondence with a single input value**
 $\Delta\Sigma$ ADCs have memory, and the output is not simply a function of a single input

ECE1371

4-11

Pipeline ADC

- **Each stage quantizes the amplified quantization error signal from the previous stage**
- **Higher throughput, lower complexity**



ECE1371

4-12

Digital Outputs

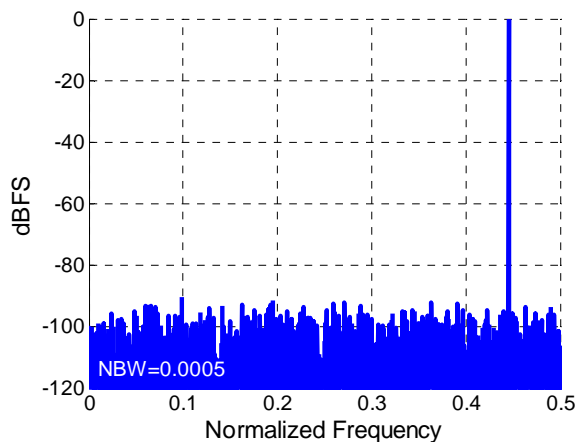
- Binary weight and add digital outputs of each stage
 - Example: 10-bit ADC
8 stages with 1.5-bit per stage, 2-bit final stage
 $D_{1...8}=\{-1,0,1\}$, $D_9=\{-1.5,-0.5,0.5,1.5\}$
 $D_{OUT}=D_1 2^8 + D_2 2^7 + D_3 2^6 + D_4 2^5 + D_5 2^4 + D_6 2^3 + D_7 2^2 + D_8 2^1 + D_9 2^0$
- 1024 output levels: 10-bit converter
1-bit per stage x 8 stages + 2-bit final stage = 10 bits

ECE1371

4-13

Sample Output Spectrum

- What is the SQNR?
Rectangular Window, $N=2048=2^{11}$

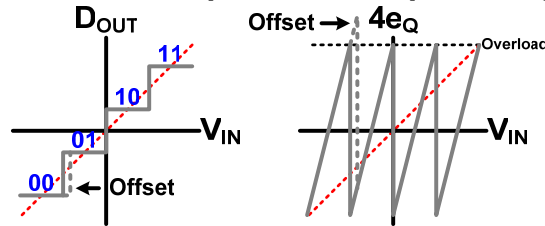


ECE1371

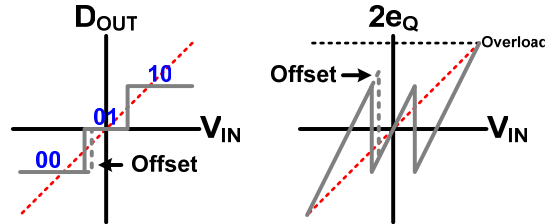
4-14

Gain and Quantization

- Using full range sensitive to offsets in A/D
Offset saturates input to subsequent stage



- Less sensitive to offsets
Fewer bits/stage, smaller gain to next stage



ECE1371

4-15

Offset Errors

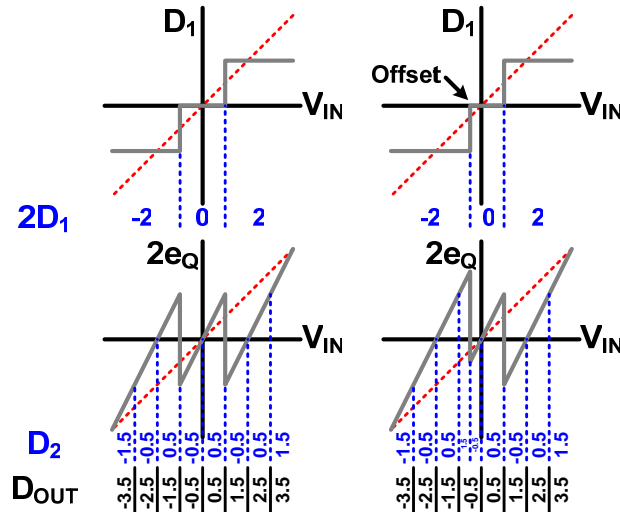
- Example: 3-bit ADC
1.5-bit stage followed by 2-bit final stage
 $D_1 = \{-1, 0, 1\}$
 $D_2 = \{-1.5, -0.5, 0.5, 1.5\}$
 $D_{OUT} = D_1 2^1 + D_2 2^0$
- With an offset error, the outputs are the same
Quantization error does not saturate the input to the subsequent stage

ECE1371

4-16

Offset Errors

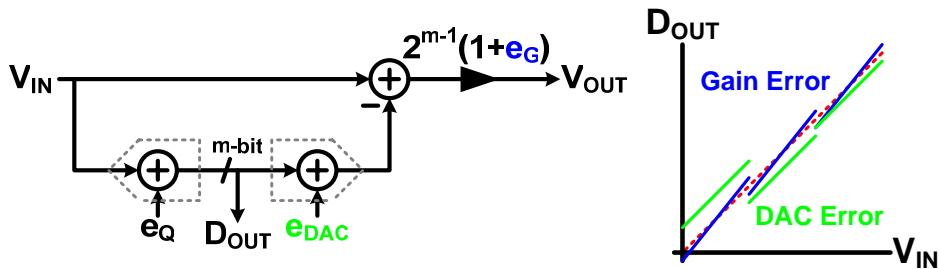
- Two Cases: No Offset; Offset present



ECE1371

4-17

Error Sources



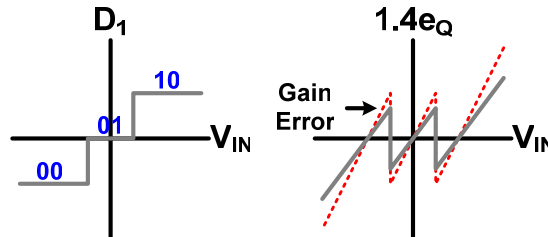
- Sub-ADC error doesn't matter
- DAC error and gain error cause discontinuity in transfer function
 - Signal dependent tones
- In a MASH, they increase noise

ECE1371

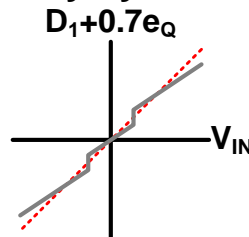
4-18

Gain Error

- Example: Assume a gain error of 30%



Sum the 2 curves assuming the residue $1.4e_Q$ is quantized perfectly by the later stages

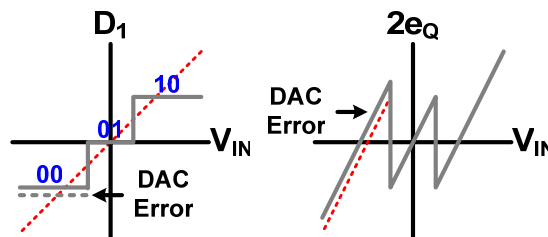


ECE1371

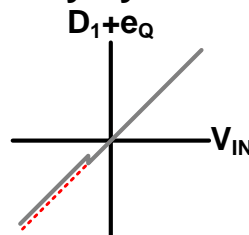
4-19

DAC Error

- Example: Assume a DAC error of ~20%



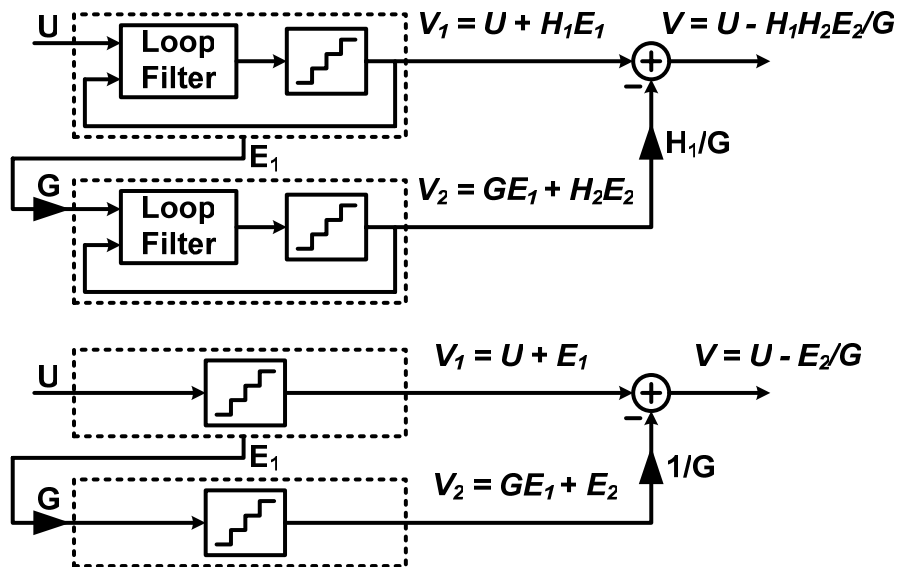
Sum the 2 curves assuming the residue is quantized perfectly by the later stages



ECE1371

4-20

Pipeline and MASH $\Delta\Sigma$ ADC



ECE1371

4-21

Motivation for SAR ADCs

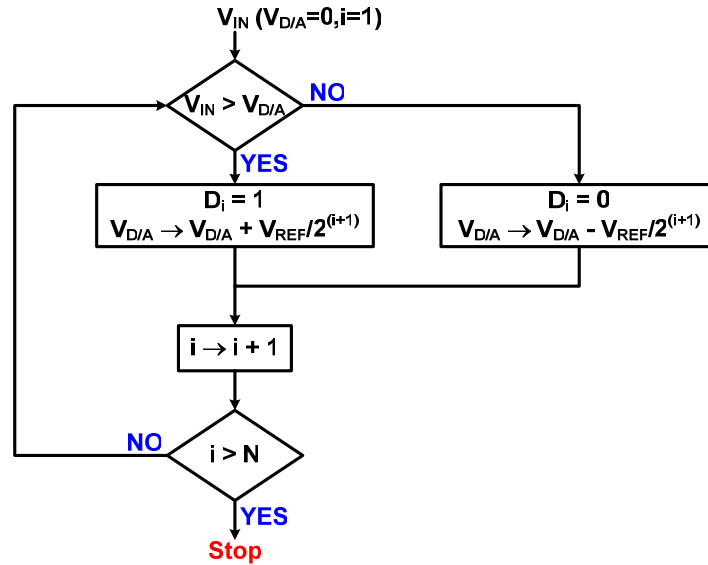
- Many ADCs sample much faster (>1 MSPS) than needed for many applications
 - Industrial sensors
 - Power line measurements
 - Audio
 - Medical imaging
- Accuracy and power are the next priorities
- SAR ADCs are low power, and like any Nyquist rate ADCs, can be oversampled for improved accuracy

ECE1371

4-22

Successive Approximation ADC

- ADC based on binary search algorithm



ECE1371

4-23

DAC-based SAR ADC

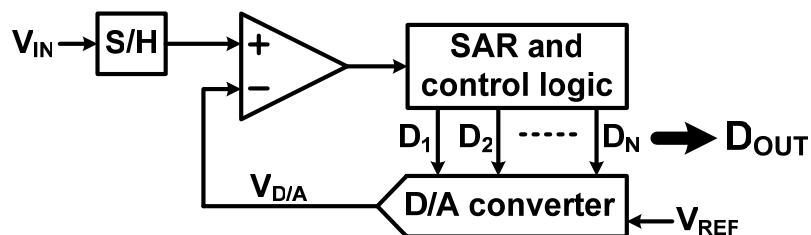
- How do we implement this algorithm?

$D_1=1, D_{2...n}=0$, check $V_{D/A}$ against V_{IN}

If $V_{IN} > V_{D/A}$, $D_1=1$

If $V_{IN} < V_{D/A}$, $D_1=0$

Now try $D_2=1$, carry on...



ECE1371

4-24

SAR Advantages

- **Useful for signals from 1 Hz to 1 MHz**
Internal clock must be faster than signal depending on the resolution
- **Very accurate and power efficient**
Less power with same resolution and bandwidth than other converters (see ISSCC)
- **Does not need internal OpAmps**
Only uses a single comparator
- **Lower kT/C noise**
No input referred noise from other stages

SAR Algorithm

- **Algorithm finds largest DAC value less than V_{IN}**
- **Every single bit acquired must be accurate to the resolution of the system**
DAC linearity
Comparator Offset
S/H offset and linearity
- **Comparator must respond to large changes**
Large overdrive to 0.5 LSB in a single bit cycle period

SAR Algorithm

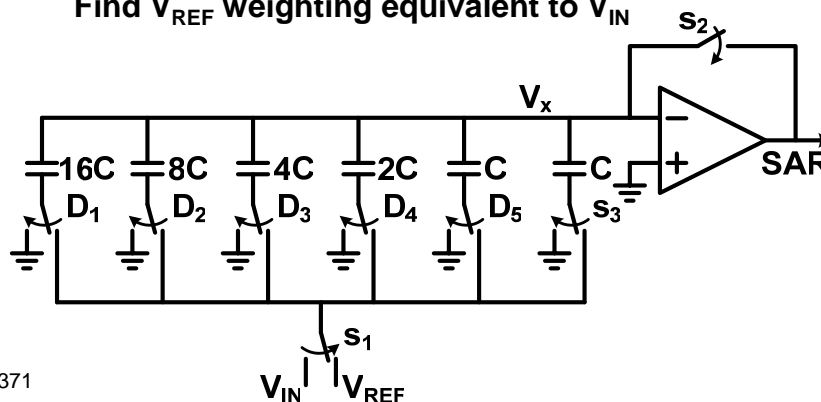
- **Bandwidth limitation**
For N-bit resolution, N bit cycles are required, reducing the effective sampling frequency by N
- **Comparison nodes must be quiet before comparator triggers**

ECE1371

4-27

Unipolar Charge-Redistribution SAR

1. Charge all caps to V_{IN} (s_2 on; s_1, s_3 off)
2. Switch caps to ground, $V_x = -V_{IN}$ (s_3 on; s_1, s_2 off)
3. Switch s_1 to V_{REF} , start bit cycling
Switch D_1 to V_{REF} , if V_x negative then keep D_1 at V_{REF}
Find V_{REF} weighting equivalent to V_{IN}



ECE1371

4-28

Unipolar Charge-Redistribution SAR

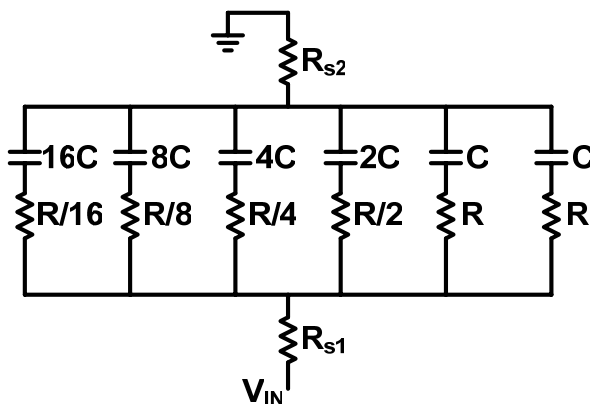
- Extra capacitor C required for exact divide by 2
- DAC capacitor array serves as Sample-and-Hold
- Switching sequence is parasitic insensitive
 - Parasitic capacitors attenuate the signal on V_x
 - Better to keep capacitor bottom plates on the V_{REF} side (not the comparator side)
- Signed conversion with added $-V_{REF}$ input
 - If $V_x < 0$ on step 2, proceed with V_{REF}
 - If $V_x > 0$ on step 2, use $-V_{REF}$, opposite comparison

ECE1371

4-29

Speed Estimate of SAR

- Model RC network when V_{IN} is charged
 - Replace switches with R's
 - Assume switches are sized proportional to capacitors



ECE1371

4-30

Speed Estimate of SAR

- Speed limited by RC time constant of capacitor array and switches

$$\tau_{eq} = (R_{s1} + R_{s2} + R/2^N)2^N C$$

For better than 0.5 LSB accuracy

$$e^{-T/\tau_{eq}} < \frac{1}{2^{N+1}}$$

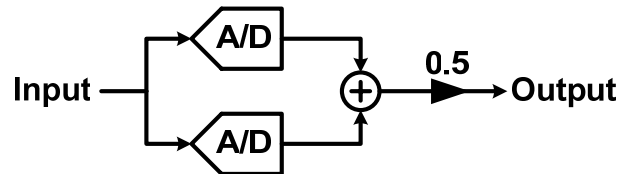
Sets minimum value for the charging time T

$$T > 0.69(N+1)(R_{s1} + R_{s2} + R/2^N)2^N C$$

**What are the
Fundamental Trade-offs
among BW, DR and P?**

DR-P Trade-Off: Part 1

- To increase DR at the expense of P, parallel two ADCs and average:



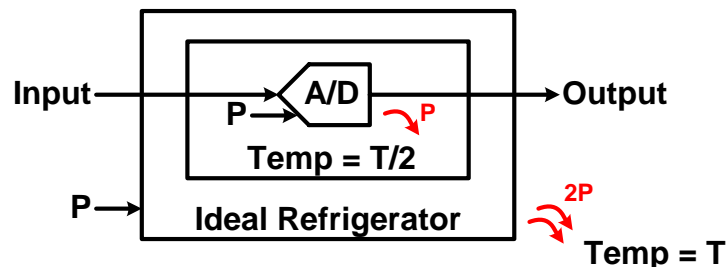
- Reduces noise by a factor of $\sqrt{2}$: DR \uparrow 3 dB, but uses twice the power: P \uparrow 3 dB
Assumes arithmetic requires no power, noise sources are uncorrelated and the source can drive two ADCs.

ECE1371

4-33

DR-P Trade-Off: Part 1b

- Can increase DR by 3 dB by reducing T by a factor of 2:



- But this also costs twice the power (based on thermodynamics)

ECE1371

4-34

DR-P Trade-Off: Part 2

- To reduce P at the expense of DR,
“cut the ADC in half”
May not be practical if the ADC is already small,
but if it can be done,
 $P \downarrow 3 \text{ dB}$ & $DR \downarrow 3 \text{ dB}$
- \therefore For an ADC of some BW

X dB in DR costs X dB in P,

or

DR (in dB) – $10\log_{10}(P)$ is a constant

Q: Is This Trade-Off Optimal?

- A: Yes, because it is bi-directional
The fact that you can (in principal) go both ways for any ADC means that no other trade-off can exist for ADCs that are optimal.
- Consider a (supposedly) optimal ADC that can get more than 3 dB increase in DR for a doubling of P
Double P, then cut that ADC in half.
The resulting ADC has the same P as the original, but more DR.

What About BW?

- Reducing BW by a factor of 2 increases DR by 3 dB but leaves P alone
Assuming the noise is white (distortion is not dominant) and that digital filtering takes no power.
- Time-interleaving two ADCs doubles BW and doubles P, but leaves DR unchanged
Assumes that interleaving is perfect (can be calibrated with no extra power).
I/Q processing also doubles BW & P @ same DR.
- In these examples,
DR (in dB) + $10\log_{10}(BW/P)$ is a constant

ECE1371

4-37

Resulting FOM

$$FOM = (DR)_{dB} + 10\log_{10} \frac{BW}{P}$$

- For a given FOM, factors of 2 in BW or P are equivalent to a 3 dB change in DR
- Should really include T, but since T is usually assumed to be 300K, omit it
Steyaert et al. $FOM = \frac{4kT \square DR \square BW}{P}$

ECE1371

4-38

Oversampled vs. Nyquist Rate

- For switched-capacitor design, assume power is dominated by kT/C noise
- Assume power is dominated by 1st stage
 - In $\Delta\Sigma$ ADCs, this is usually more accurate
 - In Pipeline ADCs, more noise is from the later stages
- Which is more power efficient?
 - For the same resolution and speed, oversampled operates N times faster, capacitor is N times smaller
 - \therefore Power is the same
 - It is the 'little things' (biasing, clocks, stage sizing, OpAmp gain, architecture) that make a big difference

Common FOM

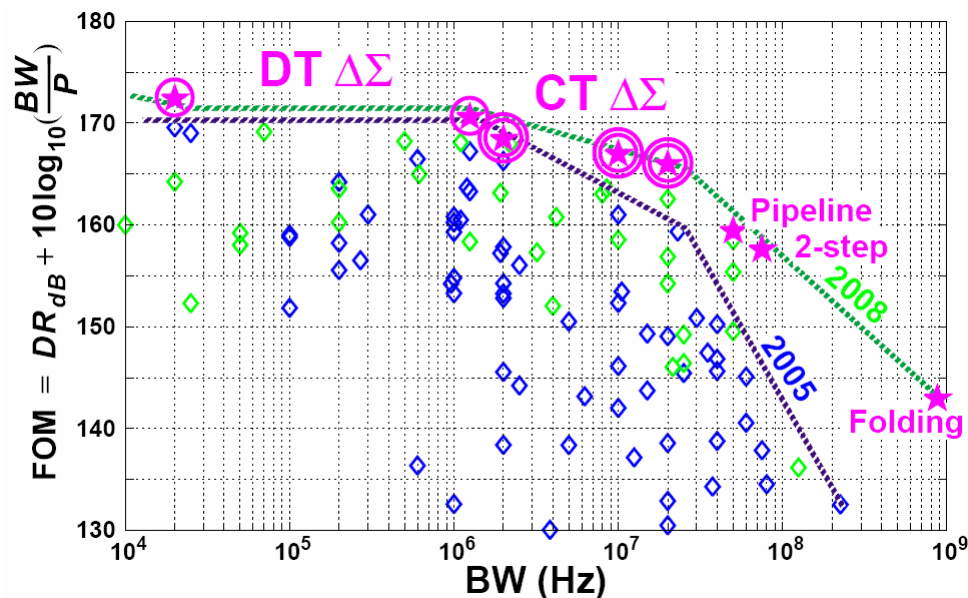
$$FOM = \frac{P}{2BW \cdot 2^{ENOB}}$$

- Units of Joules per Conversion Step
 - P in J/s, BW in 1/s, 2^{ENOB} in conversion steps
- Fundamentally incorrect:
 - 1 extra bit costs $2x P$, instead of $4x P$
 - 1 extra bit means noise is reduced by 6dB, which requires 4 parallel ADCs, not 2
- Favours lower resolution ADCs

Common FOM

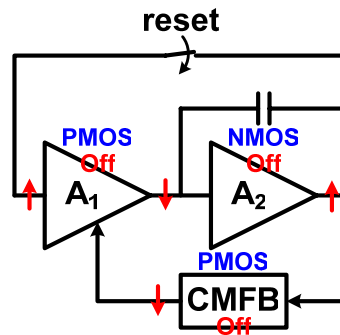
- Example: OTA dominated by thermal noise
 - SNR = Signal Power / Noise Power
 - Reduce noise power by 6 dB to get 1 more bit
 - Noise Power proportional to $1/C$
 - To reduce noise power by 6 dB, or 4x, we need to increase C by 4
 - Keep V_{EFF} and BW (g_m/C) constant
 - Increase I_D and W by 4 (like 4 OTAs in parallel)
 - OTA power increased by 4
 - \therefore 4x power required for 1 extra bit
 - Inconsistent with 'Common FOM'

FOM vs. BW



NLCOTD: Startup Circuit

How do we keep this from turning off during reset?



ECE1371

4-43

Homework

1. Determine analytically the allowable gain error for the 1st-stage of a 1.5 bit/stage 10-bit pipeline ADC so that the DNL error is less than
 - a) 2 LSB
 - b) 0.5 LSB

Now simulate the pipeline in MATLAB to do the following:

2. Plot the DNL error for both cases.
3. Plot the output spectrum for both cases with a full-scale sine wave input.
4. What is the SNDR and what did you expect it to be for both cases?

ECE1371

4-44

What You Learned Today

1. ADC performance limitations
2. Basic operation of Pipeline and Successive Approximation ADCs
3. Gain Errors in Pipeline ADCs (Homework)
4. Fundamental trade-offs between BW, DR and P and ADC FOMs

ECE1371

4-45

Projects (1)

List of $\Delta\Sigma$ projects...

(Choose OSR, order, cascaded/single-loop)

- 40MS/s 12-bit $\Delta\Sigma$ Modulator
- 2.2MS/s 14-bit $\Delta\Sigma$ Modulator
- 24kS/s 18-bit $\Delta\Sigma$ Modulator

List of Pipeline projects...

- 50MS/s 14-b Pipeline ADC
- 200MS/s 10-b Pipeline ADC

ECE1371

4-46

Projects (2)

More interesting projects...

- **25MS/s, 5th-order, 14-b $\Delta\Sigma$ Modulator**
Balmelli, JSSC Dec. 2004 (OSR=8, $f_s=200\text{MHz}$)
- **22-bit incremental (resetting $\Delta\Sigma$) ADC**
Quiquempoix, JSSC July. 2006 ('OSR'=2048, 15 S/s)
- **13-b Audio $\Delta\Sigma$ using Switched-RC integrators**
Ahn, JSSC Dec. 2005 (OSR=64, $f_s=3.1\text{MHz}$, 0.6V supply)
- **10-b 200MS/s Pipeline ADC with amplifier sharing**
Kurose, JSSC July. 2006 (two channels, I & Q)

Projects (3)

High-Speed Continuous-Time $\Delta\Sigma$ projects...

- **640MHz, 12-bit, continuous-time $\Delta\Sigma$**
Mitteregger, JSSC Dec. 2005 (OSR=16, 3rd-order)
- **300MHz, 11-bit, continuous-time $\Delta\Sigma$**
Paton, JSSC July 2004 (OSR=10, 4th-order)

Other projects...

Feel free to propose projects for approval.